Abstracts

Precisely Calibrated Coaxial-to-Microstrip Transitions Yield Improved Performance in GaAs FET Characterization

G. Kompa, M. Schlechtweg and F. van Raay. "Precisely Calibrated Coaxial-to-Microstrip Transitions Yield Improved Performance in GaAs FET Characterization." 1990 Transactions on Microwave Theory and Techniques 38.1 (Jan. 1990 [T-MTT]): 62-68.

A new approach for calibrating coaxial-to-microstrip transitions up to 26.5 GHz with high precision is presented. An ideal through, noncritical open, noncritical short, and a surface absorber are used as microstrip standards for the calibration. The calibration measurement and a novel approach in extracting the scattering parameters of the transitions are described. Error-corrected results on broad-band measurements of the scattering coefficients of packaged FET's in a hybrid circuit configuration are given.

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